

## **[Scope]**

This evaluation method evaluates the difference in EMI (Electromagnetic Interference) and EMS (Electromagnetic Susceptibility) performance and does not include performance evaluation of ESD/EOS. This method is applicable to the evaluation of semiconductor products with the same functions, no change in pin configuration and pin position, and no difference in electrical characteristics between two products to be evaluated for comparison.

## **[Overview]**

This standard describes the evaluation method to confirm the EMC performance difference of semiconductor products when there was a process change (PCN) in the semiconductor products. The conducted emissions and conducted immunity are tested for the EMC performance evaluation, and its test methods comply with IEC 61967 -4 (150  $\Omega$  method) and IEC 62132 -4 (DPI method). This standard specifies the test conditions that should be taken into consideration when evaluating EMC performance equivalence between products using these test methods.